

INFORMATION DISCLOSURE CITATION

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ATTY DOCKET NO.

P 6079.12009

SERIAL NO.

10/692,586

FILING

Oct. 23, 2003

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>[Signature]</i>	US2002/0133772 A1	9/19/02	Voorakaranam et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>[Signature]</i>	Chatterjee et al., Ardext FASTest: A New Approach For Rapid Testing of Analog ICs, http://www.ardext.com/documents/ardext_fast_technology.htm
<i>[Signature]</i>	Ram Voorakaranam, et al., "A Signature Test Framework for Rapid Production Testing in RF Circuits," Design, Automation and Test in Europe, 2002, 6 pages

EXAMINER

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10/15/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

